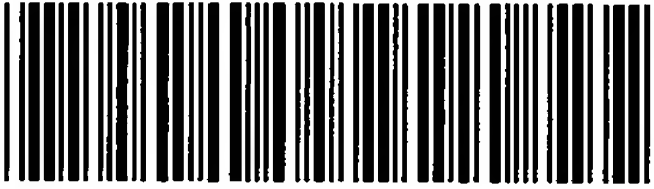


<b>Search Notes</b> 	<b>Application/Control No.</b> 10/627,057	<b>Applicant(s)/Patent under Reexamination</b> LEE, YONG GUEN	
	<b>Examiner</b> M. Wilczewski	<b>Art Unit</b> 2822	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East Search	1/31/2007	MW